


<p style="text-align: center;">Search Notes</p> 	<p>Application/Control No.</p> <p>10622294</p>	<p>Applicant(s)/Patent Under Reexamination</p> <p>CHOWN, DAVID</p>
	<p>Examiner</p> <p>Liu, Li</p>	<p>Art Unit</p> <p>2613</p>

SEARCHED			
Class	Subclass	Date	Examiner
372	102	08/03/2006	LL
398	41-43, 152, 129, 58, 122, 125	08/03/2006, 02/08/2007	LL
385	12, 24, 93, 49	08/03/2006, 02/08/2007	LL
250	25	08/03/2006	LL

SEARCH NOTES		
Search Notes	Date	Examiner
EAST		
USPAT, US-PGPUB, EPO, JPO, DERWENT, IBM_TDB	08/03/2006, 02/08/2007, 11/27/2007, 5/31-6/13, 2008	LL
Google	08/03/2006	LL
IEEE	08/03/2006	LL

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner